

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10585326	NAKASHIMA ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
	Andrew K Bohaty	4132

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
428	690	6/16/2009	A. K. Bohaty

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Inventor Name Search in PALM	6/16/2009	A. K. Bohaty
East search (see search history printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	6/16/2009-6/19/2009	A. K. Bohaty
Google NPL search	6/17/2009	A. K. Bohaty
STN structure search	6/16/2009	A. K. Bohaty
Updated East search (see search history printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	12/7/2009	A. K. Bohaty
Updated East search (see search history printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	5/11/2010	A. K. Bohaty
Updated STN structure search (see STN transcript)	5/10/2010	A. K. Bohaty
Updated East search (see search history printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	9/16/2010	A. K. Bohaty
Updated East search (see search history printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	1/6/2011	A. K. Bohaty
Updated East search (see search history printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	5/10/2011	A. K. Bohaty
Updated East search (see search history printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	10/21/2011	A. K. Bohaty
Updated STN structure search (see STN transcript)	10/21/2011	A. K. Bohaty

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>